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# DS90LV049Q Automotive LVDS Dual Line Driver and Receiver Pair

Check for Samples: DS90LV049Q

#### **FEATURES**

- AECQ-100 Grade 1
- Up to 400 Mbps Switching Rates
- Flow-Through Pinout Simplifies PCB Layout
- 50 ps Typical Driver Channel-to-Channel Skew
- 50 ps Typical Receiver Channel-to-Channel Skew
- 3.3 V Single Power Supply Design
- TRI-STATE Output Control
- Internal Fail-Safe Biasing of Receiver Inputs
- Low Power Dissipation (70 mW at 3.3 V Static)
- High Impedance on LVDS Outputs on Power Down
- Conforms to TIA/EIA-644-A LVDS Standard
- Available in Low Profile 16 Pin TSSOP Package

## **Connection Diagram**

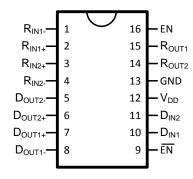


Figure 1. TSSOP Package See Package Number PW0016A

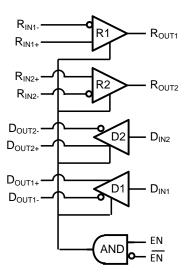
#### DESCRIPTION

The DS90LV049Q is a dual CMOS flow-through differential line driver-receiver pair designed for applications requiring ultra low power dissipation, exceptional noise immunity, and high data throughput. The device is designed to support data rates in excess of 400 Mbps utilizing Low Voltage Differential Signaling (LVDS) technology.

The DS90LV049Q drivers accept LVTTL/LVCMOS signals and translate them to LVDS signals. The receivers accept LVDS signals and translate them to 3 V CMOS signals. The LVDS input buffers have internal failsafe biasing that places the outputs to a known H (high) state for floating receiver inputs. In addition, the DS90LV049Q supports a TRI-STATE function for a low idle power state when the device is not in use.

The EN and  $\overline{\text{EN}}$  inputs are ANDed together and control the TRI-STATE outputs. The enables are common to all four gates.

# **Functional Diagram**



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Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



#### **Truth Table**

EN	EN	LVDS Out	LVCMOS Out
L or Open	L or Open	OFF	OFF
Н	L or Open	ON	ON
L or Open	Н	OFF	OFF
Н	Н	OFF	OFF



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

Absolute Maximum Ratings (1)(2)

Absolute maximum ratings	1
Supply Voltage (V <sub>DD</sub> )	-0.3 V to +4 V
LVCMOS Input Voltage (D <sub>IN</sub> )	$-0.3 \text{ V to } (V_{DD} + 0.3 \text{ V})$
LVDS Input Voltage (R <sub>IN+</sub> , R <sub>IN-</sub> )	-0.3 V to +3.9 V
Enable Input Voltage (EN, EN)	$-0.3 \text{ V to } (V_{DD} + 0.3 \text{ V})$
LVCMOS Output Voltage (R <sub>OUT</sub> )	$-0.3 \text{ V to } (V_{DD} + 0.3 \text{ V})$
LVDS Output Voltage (D <sub>OUT+</sub> , D <sub>OUT-</sub> )	-0.3 V to +3.9 V
LVCMOS Output Short Circuit Current (R <sub>OUT</sub> )	100 mA
LVDS Output Short Circuit Current (D <sub>OUT+</sub> , D <sub>OUT-</sub> )	24 mA
LVDS Output Short Circuit Current Duration (D <sub>OUT+</sub> , D <sub>OUT-</sub> )	Continuous
Storage Temperature Range	−65°C to +150°C
Lead Temperature Range	
Soldering (4 sec.)	+260°C
Maximum Junction Temperature	+135°C
Maximum Package Power Dissipation @ +25°C	
PW0016A Package	1146 mW
Derate PW0016A Package	10.4 mW/°C above +25°C
Package Thermal Resistance (4-Layer, 2 oz. Cu, JEDEC)	
$\theta_{JA}$	96.0°C/W
$\theta_{ m JC}$	30.0°C/W
ESD Rating	
HBM <sup>(3)</sup>	≥ 8 kV
MM <sup>(4)</sup>	≥ 250 V
CDM <sup>(5)</sup>	≥ 1250 V

- (1) Absolute Maximum Ratings are those values beyond which the safety of the device cannot be ensured. They are not meant to imply that the devices should be operated at these limits. Electrical Characteristics specifies conditions of device operation.
- (2) If Military/Aerospace specified devices are required, please contact the Texas Instruments Sales Office/ Distributors for availability and specifications.
- (3) Human Body Model, applicable std. JESD22-A114C
- (4) Machine Model, applicable std. JESD22-A115-A
- (5) Field Induced Charge Device Model, applicable std. JESD22-C101-C

## **Recommended Operating Conditions**

	Min	Тур	Max	Units
Supply Voltage (V <sub>DD</sub> )	+3.0	+3.3	+3.6	٧
Operating Free Air Temperature (T <sub>A</sub> )	-40	+25	+125	ů

Product Folder Links: DS90LV049Q

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#### **Electrical Characteristics**

Over supply voltage and operating temperature ranges, unless otherwise specified. (1)(2)(3)

	Parameter	Test Conditions	Pin	Min	Тур	Max	Units
LVCMOS	S Input DC Specifications (Driver Input	ts, ENABLE Pins)					
V <sub>IH</sub>	Input High Voltage			2.0		$V_{DD}$	V
$V_{IL}$	Input Low Voltage		D <sub>IN</sub>	GND		0.8	V
I <sub>IH</sub>	Input High Current	$V_{IN} = V_{DD}$	EN	-10	1	+10	μΑ
I <sub>IL</sub>	Input Low Current	V <sub>IN</sub> = GND	EN	-10	-0.1	+10	μΑ
$V_{CL}$	Input Clamp Voltage	I <sub>CL</sub> = −18 mA		-1.5	-0.6		V
LVDS O	utput DC Specifications (Driver Output	ts)	•		•	•	
V <sub>OD</sub>	Differential Output Voltage			250	350	450	mV
$\Delta V_{OD}$	Change in Magnitude of V <sub>OD</sub> for Complementary Output States	R <sub>L</sub> = 100 Ω			1	35	mV
$V_{OS}$	Offset Voltage	(Figure 2)		1.125	1.23	1.375	V
$\Delta V_{OS}$	Change in Magnitude of V <sub>OS</sub> for Complementary Output States				1	25	mV
I <sub>OS</sub>	Output Short Circuit Current (4)	ENABLED, $D_{IN} = V_{DD}$ , $D_{OUT+} = 0$ V or $D_{IN} = GND$ , $D_{OUT-} = 0$ V	D <sub>OUT</sub> - D <sub>OUT</sub> +		-5.8	-9.0	mA
I <sub>OSD</sub>	Differential Output Short Circuit Current (4)	ENABLED, V <sub>OD</sub> = 0 V			-5.8	-9.0	mA
I <sub>OFF</sub>	Power-off Leakage	$V_{OUT} = 0 \text{ V or } 3.6 \text{ V}$ $V_{DD} = 0 \text{ V or Open}$		-20	±1	+20	μA
I <sub>OZ</sub>	Output TRI-STATE Current	$EN = 0 V \text{ and } \overline{EN} = V_{DD}$ $V_{OUT} = 0 V \text{ or } V_{DD}$		-10	±1	+10	μA
LVDS In	put DC Specifications (Receiver Input	s)					
$V_{TH}$	Differential Input High Threshold	V <sub>CM</sub> = 1.2 V, 0.05 V, 2.35 V			-15	35	mV
$V_{TL}$	Differential Input Low Threshold	V <sub>CM</sub> = 1.2 V, 0.03 V, 2.33 V		-100	-15		mV
$V_{CMR}$	Common-Mode Voltage Range	$V_{ID} = 100 \text{ mV}, V_{DD} = 3.3 \text{ V}$	R <sub>IN+</sub>	0.05		3	V
la.	Input Current	$V_{DD}$ =3.6 V $V_{IN}$ =0 V or 2.8 V	R <sub>IN-</sub>	-12	±4	+12	μA
I <sub>IN</sub>	input current	$V_{DD}$ =0 V $V_{IN}$ =0 V or 2.8 V or 3.6 V		-10	±1	+10	μΑ
LVCMOS	Output DC Specifications (Receiver	Outputs)					
$V_{OH}$	Output High Voltage	$I_{OH} = -0.4 \text{ mA}, V_{ID} = 200 \text{ mV}$		2.7	3.3		V
$V_{OL}$	Output Low Voltage	$I_{OL} = 2 \text{ mA}, V_{ID} = 200 \text{ mV}$	R <sub>OUT</sub>		0.05	0.25	V
$I_{OZ}$	Output TRI-STATE Current	Disabled, $V_{OUT} = 0 \text{ V or } V_{DD}$		-10	±1	+10	μΑ
General	DC Specifications						
$I_{DD}$	Power Supply Current (5)	EN = 3.3 V	V		21	35	mA
I <sub>DDZ</sub>	TRI-State Supply Current	EN = 0 V	$V_{DD}$		15	25	mA

<sup>(1)</sup> Current into device pins is defined as positive. Current out of device pins is defined as negative. All voltages are referenced to ground except:  $V_{TH}$ ,  $V_{DD}$  and  $\Delta V_{DD}$ .

All typical values are given for:  $V_{DD} = +3.3 \text{ V}$ ,  $V_{DD} = +3$ 

Product Folder Links: DS90LV049Q

their outputs. The typical range of the resistor values is 90  $\Omega$  to 110  $\Omega$ .

Output short circuit current ( $l_{OS}$ ) is specified as magnitude only, minus sign indicates direction only. Both driver and receiver inputs are static. All LVDS outputs have 100  $\Omega$  load. All LVCMOS outputs are floating. None of the outputs have any lumped capacitive load.



#### **Switching Characteristics**

Over supply voltage and operating temperature ranges, unless otherwise specified. (1)(2)

	Parameter	Test Conditions	Min	Тур	Max	Units
LVDS O	Outputs (Driver Outputs)					
t <sub>PHLD</sub>	Differential Propagation Delay High to Low			0.7	2	ns
t <sub>PLHD</sub>	Differential Propagation Delay Low to High			0.7	2	ns
t <sub>SKD1</sub>	Differential Pulse Skew  t <sub>PHLD</sub> - t <sub>PLHD</sub>   (3) (4)		0	0.05	0.4	ns
t <sub>SKD2</sub>	Differential Channel-to-Channel Skew (3) (5)	$R_L = 100 \Omega$ (Figure 3 and Figure 4)	0	0.05	0.5	ns
t <sub>SKD3</sub>	Differential Part-to-Part Skew (3) (6)	(Figure 5 and Figure 4)	0		1.0	ns
t <sub>TLH</sub>	Rise Time (3)		0.2	0.4	1	ns
t <sub>THL</sub>	Fall Time (3)		0.2	0.4	1	ns
t <sub>PHZ</sub>	Disable Time High to Z			1.5	3	ns
$t_{PLZ}$	Disable Time Low to Z	$R_L = 100 \Omega$		1.5	3	ns
t <sub>PZH</sub>	Enable Time Z to High	(Figure 5 and Figure 6)	1	3	6	ns
t <sub>PZL</sub>	Enable Time Z to Low		1	3	6	ns
$f_{MAX}$	Maximum Operating Frequency (7)			250		MHz
LVCMO	S Outputs (Receiver Outputs)					
t <sub>PHL</sub>	Propagation Delay High to Low		0.5	2	3.5	ns
t <sub>PLH</sub>	Propagation Delay Low to High		0.5	2	3.5	ns
t <sub>SK1</sub>	Pulse Skew  t <sub>PHL</sub> - t <sub>PLH</sub>   (8)		0	0.05	0.4	ns
t <sub>SK2</sub>	Channel-to-Channel Skew (9)	(Figure 7 and Figure 8)	0	0.05	0.5	ns
t <sub>SK3</sub>	Part-to-Part Skew (10)		0		1.0	ns
t <sub>TLH</sub>	Rise Time <sup>(3)</sup>		0.3	0.9	1.4	ns
t <sub>THL</sub>	Fall Time <sup>(3)</sup>		0.3	0.75	1.4	ns
t <sub>PHZ</sub>	Disable Time High to Z		3	5.6	8	ns
t <sub>PLZ</sub>	Disable Time Low to Z	(Figure 0 and Figure 40)	3	5.4	8	ns
t <sub>PZH</sub>	Enable Time Z to High	(Figure 9 and Figure 10)	2.5	4.6	7	ns
t <sub>PZL</sub>	Enable Time Z to Low		2.5	4.6	7	ns
f <sub>MAX</sub>	Maximum Operating Frequency (11)			250		MHz

- (1) All typical values are given for: V<sub>DD</sub> = +3.3 V, T<sub>A</sub> = +25°C.
- (2) Generator waveform for all tests unless otherwise specified: f = 1 MHz,  $Z_0 = 50 \Omega$ ,  $t_f \le 1$  ns, and  $t_f \le 1$  ns.
- (3) These parameters are ensured by design. The limits are based on statistical analysis of the device performance over PVT (process, voltage, temperature) ranges.
- (4) t<sub>SKD1</sub> or differential pulse skew is defined as |t<sub>PHLD</sub> t<sub>PLHD</sub>|. It is the magnitude difference in the differential propagation delays between the positive going edge and the negative going edge of the same driver channel.
- (5) t<sub>SKD2</sub> or differential channel-to-channel skew is defined as the magnitude difference in the differential propagation delays between two driver channels on the same device.
- (6) t<sub>SKD3</sub> or differential part-to-part skew is defined as |t<sub>PLHD Max</sub> t<sub>PLHD Min</sub>| or |t<sub>PHLD Max</sub> t<sub>PHLD Min</sub>|. It is the difference between the minimum and maximum specified differential propagation delays. This specification applies to devices at the same V<sub>DD</sub> and within 5°C of each other within the operating temperature range.
- (7)  $f_{MAX}$  generator input conditions:  $t_r = t_f < 1$  ns (0% to 100%), 50% duty cycle, 0 V to 3 V. Output Criteria: duty cycle = 45%/55%,  $V_{OD} > 250$  mV, all channels switching.
- (8) t<sub>SK1</sub> or pulse skew is defined as |t<sub>PHL</sub> t<sub>PLH</sub>|. It is the magnitude difference in the propagation delays between the positive going edge and the negative going edge of the same receiver channel.
- (9) t<sub>SK2</sub> or channel-to-channel skew is defined as the magnitude difference in the propagation delays between two receiver channels on the same device.
- (10) t<sub>SK3</sub> or part-to-part skew is defined as |t<sub>PLH Max</sub> = t<sub>PLH Min</sub>| or |t<sub>PHL Max</sub> = t<sub>PHL Min</sub>|. It is the difference between the minimum and maximum specified propagation delays. This specification applies to devices at the same V<sub>DD</sub> and within 5°C of each other within the operating temperature range.
- (11)  $f_{MAX}$  generator input conditions:  $t_r = t_f < 1$  ns (0% to 100%), 50% duty cycle,  $V_{ID} = 200$  mV,  $V_{CM} = 1.2$  V . Output Criteria: duty cycle = 45%/55%,  $V_{OH} > 2.7$  V,  $V_{OL} < 0.25$  V, all channels switching.

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#### **Parameter Measurement Information**

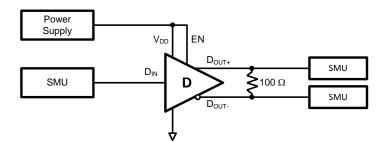


Figure 2. Driver  $\rm V_{OD}$  and  $\rm V_{OS}$  Test Circuit

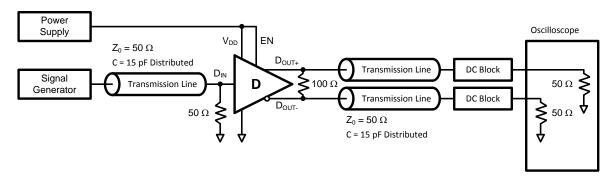


Figure 3. Driver Propagation Delay and Transition Time Test Circuit

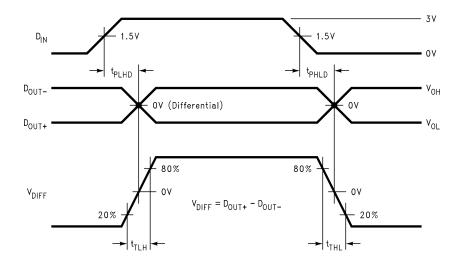


Figure 4. Driver Propagation Delay and Transition Time Waveforms



## **Parameter Measurement Information (continued)**

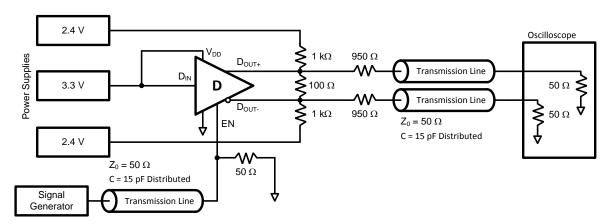


Figure 5. Driver TRI-STATE Delay Test Circuit

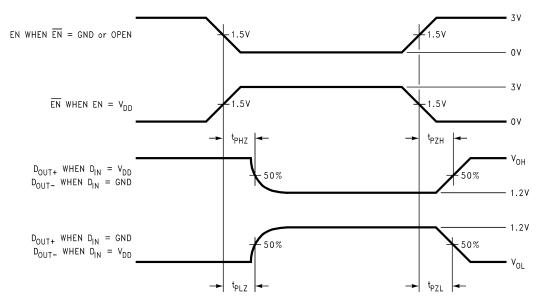


Figure 6. Driver TRI-STATE Delay Waveform

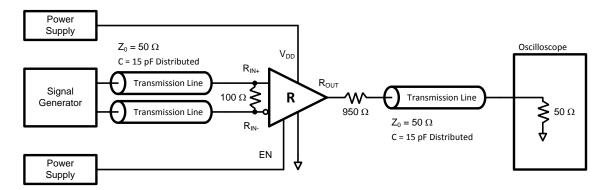


Figure 7. Receiver Propagation Delay and Transition Time Test Circuit

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# **Parameter Measurement Information (continued)**

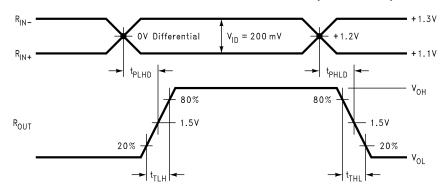


Figure 8. Receiver Propagation Delay and Transition Time Waveforms

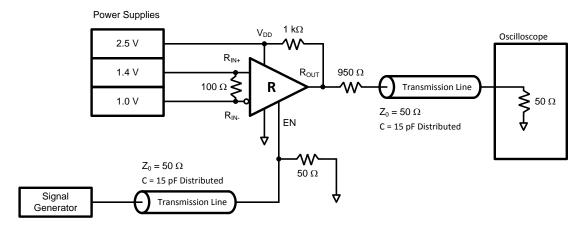


Figure 9. Receiver TRI-STATE Delay Test Circuit



#### Parameter Measurement Information (continued)

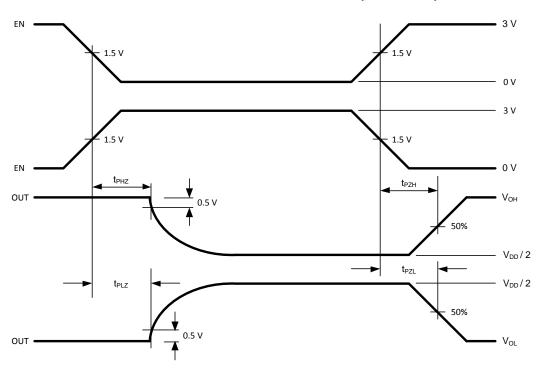


Figure 10. Receiver TRI-STATE Delay Waveforms

**Typical Application** 

# DATA INPUT LVDS Driver LVDS Receiver DATA OUTPUT

Figure 11. Point-to-Point Application

#### APPLICATION INFORMATION

General application guidelines and hints for LVDS drivers and receivers may be found in the following application notes: LVDS Owner's Manual (lit #550062-003), AN-805 (SNOA233), AN-808 (SNLA028), AN-903 (SNLA034), AN-916 (SNLA219, AN-971(SNLA165), AN-977 (SNLA166).

LVDS drivers and receivers are intended to be primarily used in an uncomplicated point-to-point configuration as is shown in Figure 11. This configuration provides a clean signaling environment for the fast edge rates of the drivers. The receiver is connected to the driver through a balanced media which may be a standard twisted pair cable, a parallel pair cable, or simply PCB traces. Typically, the characteristic differential impedance of the media is in the range of 100  $\Omega$ . A termination resistor of 100  $\Omega$  (selected to match the media), and is located as close to the receiver input pins as possible. The termination resistor converts the driver output current (current mode) into a voltage that is detected by the receiver. Other configurations are possible such as a multi-receiver configuration, but the effects of a mid-stream connector(s), cable stub(s), and other impedance discontinuities as well as ground shifting, noise margin limits, and total termination loading must be taken into account.

The TRI-STATE function allows the device outputs to be disabled, thus obtaining an even lower power state when the transmission of data is not required.

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The DS90LV049Q has a flow-through pinout that allows for easy PCB layout. The LVDS signals on one side of the device easily allows for matching electrical lengths of the differential pair trace lines between the driver and the receiver as well as allowing the trace lines to be close together to couple noise as common-mode. Noise isolation is achieved with the LVDS signals on one side of the device and the TTL signals on the other side.

#### POWER DECOUPLING RECOMMENDATIONS

Bypass capacitors must be used on power pins. Use high frequency ceramic (surface mount is recommended) 0.1  $\mu$ F and 0.001  $\mu$ F capacitors in parallel at the power supply pin with the smallest value capacitor closest to the device supply pin. Additional scattered capacitors over the printed circuit board will improve decoupling. Multiple vias should be used to connect the decoupling capacitors to the power planes. A 10  $\mu$ F (35 V) or greater solid tantalum capacitor should be connected at the power entry point on the printed circuit board between the supply and ground.

#### PC BOARD CONSIDERATIONS

Use at least 4 PCB layers (top to bottom); LVDS signals, ground, power, TTL signals.

Isolate TTL signals from LVDS signals, otherwise the TTL may couple onto the LVDS lines. It is best to put TTL and LVDS signals on different layers which are isolated by a power/ground plane(s).

Keep drivers and receivers as close to the (LVDS port side) connectors as possible.

#### **DIFFERENTIAL TRACES**

Use controlled impedance traces which match the differential impedance of your transmission medium (that is, cable) and termination resistor. Run the differential pair trace lines as close together as possible as soon as they leave the IC (stubs should be < 10 mm long). This will help eliminate reflections and ensure noise is coupled as common-mode. In fact, we have seen that differential signals which are 1 mm apart radiate far less noise than traces 3 mm apart since magnetic field cancellation is much better with the closer traces. In addition, noise induced on the differential lines is much more likely to appear as common-mode which is rejected by the receiver.

Match electrical lengths between traces to reduce skew. Skew between the signals of a pair means a phase difference between signals which destroys the magnetic field cancellation benefits of differential signals and EMI will result. (Note the velocity of propagation, v = c/Er where c (the speed of light) = 0.2997 mm/ps or 0.0118 in/ps). Do not rely solely on the autoroute function for differential traces. Carefully review dimensions to match differential impedance and provide isolation for the differential lines. Minimize the number or vias and other discontinuities on the line.

Avoid 90° turns (these cause impedance discontinuities). Use arcs or 45° bevels.

Within a pair of traces, the distance between the two traces should be minimized to maintain common-mode rejection of the receivers. On the printed circuit board, this distance should remain constant to avoid discontinuities in differential impedance. Minor violations at connection points are allowable.

#### **TERMINATION**

Use a termination resistor which best matches the differential impedance or your transmission line. The resistor should be between 90  $\Omega$  and 130  $\Omega$ . Remember that the current mode outputs need the termination resistor to generate the differential voltage. LVDS will not work without resistor termination. Typically, connecting a single resistor across the pair at the receiver end will suffice.

Surface mount 1% to 2% resistors are best. PCB stubs, component lead, and the distance from the termination to the receiver inputs should be minimized. The distance between the termination resistor and the receiver should be < 10 mm (12 mm MAX).

#### PROBING LVDS TRANSMISSION LINES

Always use high impedance (> 100 k $\Omega$ ), low capacitance (< 2 pF) scope probes with a wide bandwidth (1 GHz) scope. Improper probing will give deceiving results.

Product Folder Links: DS90LV049Q



#### CABLES AND CONNECTORS, GENERAL COMMENTS

When choosing cable and connectors for LVDS it is important to remember:

Use controlled impedance media. The cables and connectors you use should have a matched differential impedance of about 100  $\Omega$ . They should not introduce major impedance discontinuities.

Balanced cables (for example, twisted pair) are usually better than unbalanced cables (ribbon cable, simple coax.) for noise reduction and signal quality. Balanced cables tend to generate less EMI due to field canceling effects and also tend to pick up electromagnetic radiation a common-mode (not differential mode) noise which is rejected by the receiver.

#### **FAIL-SAFE FEATURE**

An LVDS receiver is a high gain, high speed device that amplifies a small differential signal (20 mV) to CMOS logic levels. Due to the high gain and tight threshold of the receiver, care should be taken to prevent noise from appearing as a valid signal.

The receiver's internal fail-safe circuitry is designed to source/sink a small amount of current, providing fail-safe protection (a stable known state of HIGH output voltage) for floating receiver inputs.

The DS90LV049Q has two receivers, and if an application requires a single receiver, the unused receiver inputs should be left OPEN. Do not tie unused receiver inputs to ground or any other voltages. The input is biased by internal high value pull up and pull down current sources to set the output to a HIGH state. This internal circuitry will ensure a HIGH, stable output state for open inputs.

External lower value pull up and pull down resistors (for a stronger bias) may be used to boost fail-safe in the presence of higher noise levels. The pull up and pull down resistors should be in the 5 k $\Omega$  to 15 k $\Omega$  range to minimize loading and waveform distortion to the driver. The common-mode bias point should be set to approximately 1.2 V (less than 1.75 V) to be compatible with the internal circuitry.

For more information on failsafe biasing of LVDS interfaces, please refer to AN-1194 (SNLA051).

#### **PIN DESCRIPTIONS**

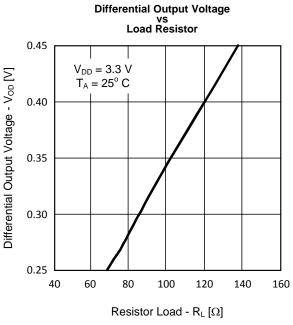
Pin No.	Name	Description
10, 11	D <sub>IN</sub>	Driver input pins, LVCMOS levels. There is a pull-down current source present.
6, 7	D <sub>OUT+</sub>	Non-inverting driver output pins, LVDS levels.
5, 8	D <sub>OUT</sub> -	Inverting driver output pins, LVDS levels.
2, 3	R <sub>IN+</sub>	Non-inverting receiver input pins, LVDS levels. There is a pull-up current source present.
1, 4	R <sub>IN-</sub>	Inverting receiver input pins, LVDS levels. There is a pull-down current source present.
14, 15	R <sub>OUT</sub>	Receiver output pins, LVCMOS levels.
9, 16	EN, EN	Enable and Disable pins. There are pull-down current sources present at both pins.
12	$V_{DD}$	Power supply pin.
13	GND	Ground pin.

Product Folder Links: DS90LV049Q

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# **Typical Performance Curves**





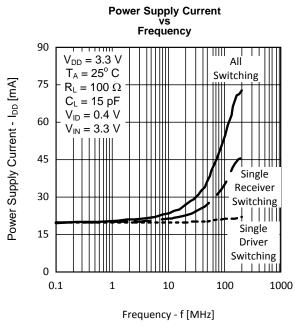


Figure 13.

## SNLS300D -MAY 2008-REVISED APRIL 2013



# **REVISION HISTORY**

Cł	anges from Revision C (April 2013) to Revision D	Ра	ıge
•	Changed layout of National Data Sheet to TI format		11

www.ti.com 23-May-2025

#### PACKAGING INFORMATION

Orderable part number	Status	Material type	Package   Pins	Package qty   Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
DS90LV049QMT/NOPB	Active	Production	TSSOP (PW)   16	92   TUBE	Yes	SN	Level-1-260C-UNLIM	-40 to 125	90LV049 QMT
DS90LV049QMT/NOPB.A	Active	Production	TSSOP (PW)   16	92   TUBE	Yes	SN	Level-1-260C-UNLIM	-40 to 125	90LV049 QMT
DS90LV049QMTX/NOPB	Active	Production	TSSOP (PW)   16	2500   LARGE T&R	Yes	SN	Level-1-260C-UNLIM	-40 to 125	90LV049 QMT
DS90LV049QMTX/NOPB.A	Active	Production	TSSOP (PW)   16	2500   LARGE T&R	Yes	SN	Level-1-260C-UNLIM	-40 to 125	90LV049 QMT

<sup>(1)</sup> Status: For more details on status, see our product life cycle.

- (3) RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.
- (4) Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.
- (5) MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.
- (6) Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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# **PACKAGE OPTION ADDENDUM**

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# **PACKAGE MATERIALS INFORMATION**

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## TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	•	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
DS90LV049QMTX/NOPB	TSSOP	PW	16	2500	330.0	12.4	6.95	5.6	1.6	8.0	12.0	Q1

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#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
DS90LV049QMTX/NOPB	TSSOP	PW	16	2500	367.0	367.0	35.0

# **PACKAGE MATERIALS INFORMATION**

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## **TUBE**



#### \*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
DS90LV049QMT/NOPB	PW	TSSOP	16	92	495	8	2514.6	4.06
DS90LV049QMT/NOPB.A	PW	TSSOP	16	92	495	8	2514.6	4.06



SMALL OUTLINE PACKAGE



#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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